

Notice of References Cited	Application/Control No. 09/963,788		Applicant(s)/Patent Under Reexamination FREUND ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,571,401	11-1996	Lewis et al.	205/787
	B	US-2003/0109056	06-2003	Vossmeyer et al.	436/169
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 99/21934	05-1999	AU	MULVANEY et al.	-
	O	WO 00/14520	03-2000	FR	PEREZ et al.	-
	P	EP 1120648 A1	08-2001	European Patent	NEMORI et al.	G01N 31/00
	Q	JP 2000266753 A	09-2000	Japan	NEMORI, RIYOUICHI	G01N 33/68
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Scott et al. "Laser Desorption FT-MS Exchange Studies of Air-Oxidized Alkanethiol Self-Assembled Monolayers on Gold", Ana Chem., 1997, v. 69, pp. 2636-2639
	V	Wohltjen et al. "Colloidal Metal-Insulator-Metal Ensemble Chemiresistor Sensor", Anal. Chem., 1998, v. 70, No. 14, pp. 2856-2859
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.